

UTC UNISONIC TECHNOLOGIES CO., LTD

UT2315-H **Preliminary** Power MOSFET

-3.3A, -20V P-CHANNEL **ENHANCEMENT MODE POWER MOSFET**

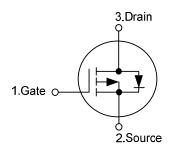
DESCRIPTION

The UTC UT2315-H is P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

FEATURES

- * Extremely low on-resistance due to high density cell
- * Perfect thermal performance and electrical capability with advanced technology of trench process





ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking
Lead Free	Halogen Free	Package	1	2	3	Packing
UT2315L-AE2-R	UT2315G-AE2-R	SOT-23-3	G	S	D	Tape Reel

Note: Pin Assignment: G: Gate S: Source D: Drain



MARKING



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SOT-23-3

(JEDEC TO-236)

■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C, unless otherwise noted)

PARAMETER	SYMBOL	RATINGS	UNIT	
Drain-Source Voltage	V_{DSS}	-20	V	
Gate-Source Voltage	V _{GSS}	±10	V	
Continuous Drain Current	I _D	-3.3	Α	
Pulsed Drain Current	I _{DM}	-13.2	Α	
Peak Diode Recovery dv/dt (Note 4)	dv/dt	2.5	V/ns	
Power Dissipation (T _C =25°C) (Note 3)	P _D	1.56	W	
Junction Temperature	TJ	+150	°C	
Storage Temperature	T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. Surface mounted on 1 in 2 copper pad of FR4 board.
- 4. $I_{SD} \le 3.3 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL CHARACTERISTICS

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient (PCB mounted)	θ_{JA}	80	°C/W

Note: Surface Mounted on FR4 board t ≤ 5 sec.

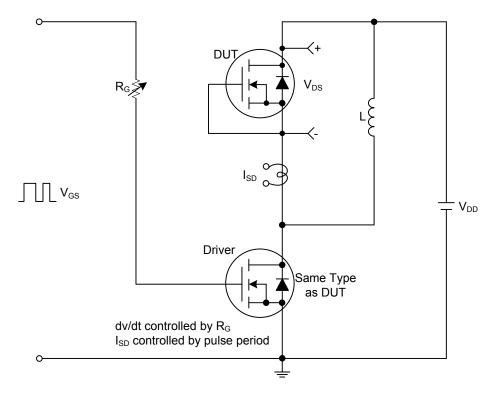
■ **ELECTRICAL CHARACTERISTICS** (T_J = 25°C, unless otherwise specified)

DADAMETED	OVARDOL	TEGT COMPLETIONS	MIN	TVD	N 4 A 3 /	LINIT		
PARAMETER	SYMBOL	TEST CONDITIONS		TYP	MAX	UNII		
OFF CHARACTERISTICS		1	l	1	1			
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =-250μA	-20			V		
Drain-Source Leakage Current	I _{DSS}	$V_{DS} = -20V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			-1	μΑ		
Brain Course Edukage Carrent		$V_{DS} = -16V, V_{GS} = 0V, T_{J} = 125^{\circ}C$			-10	μΑ		
Gate-Source Leakage Current	I _{GSS}	$V_{GS} = \pm 10V, V_{DS} = 0V$			±100	nΑ		
Breakdown Voltage Temperature Coefficient	ΔBV _{DSS} /ΔT _J	Reference to 25°C, I _D =-1mA		-0.01		V/°C		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}$, $I_D = -250 \mu A$	-0.3	-0.6	-1.0	V		
	R _{DS(ON)}	V_{GS} =-4.5V, I_D =-3.0A		77	85	mΩ		
Static Drain-Source On-State Resistance		V_{GS} =-2.5V, I_D =-2.0A		103	120	mΩ		
		V _{GS} =-1.8V, I _D =-1.0A		138	170	mΩ		
DYNAMIC PARAMETERS ^b								
Input Capacitance	C _{ISS}			350		pF		
Output Capacitance	Coss	V _{DS} =-15V, V _{GS} =0V, f =1.0MHz		65		рF		
Reverse Transfer Capacitance	C _{RSS}			50		pF		
SWITCHING PARAMETERS ^b								
Total Gate Charge (Note 1)	Q_{G}			4.8		nC		
Gate Source Charge	Q_{GS}	V_{GS} =-10V, V_{GS} =-4.5V, I_{D} =-3.0A		0.5		nC		
Gate Drain Charge	Q_{GD}			1.9		nC		
Turn-ON Delay Time (Note 1)	t _{D(ON)}			3.5		ns		
Turn-ON Rise Time	t _R	$V_{DD} = -10V$, $V_{GS} = -4.5V$, $I_{D} = -1.0A$		12.6		ns		
Turn-OFF Delay Time	t _{D(OFF)}	$R_G = 25\Omega$		32.6		ns		
Turn-OFF Fall-Time	t _F	7		8.4		ns		
SOURCE- DRAIN DIODE RATINGS AND	CHARACTE	RISTICS						
Maximum Body-Diode Continuous					2.2	_		
Current	I _S	V _G =V _D =0V , Force Current			-3.3	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				-13.2	Α		
Drain-Source Diode Forward Voltage	V_{SD}	I _S =-1.0A, V _{GS} =0V, T _J = 25°C			-1.0	V		
Reverse Recovery Time (Note 1)	t _{rr}			3140		ns		
Reverse Recovery Charge	Q _{rr}	I_S =-1.0A, V_{GS} =0V, dI_F/dt =100A/ μ s		20		μC		
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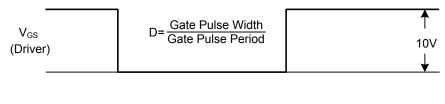
Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤2%.

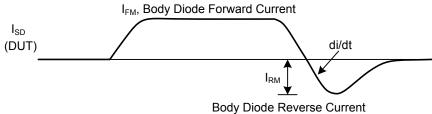
^{2.} Essentially independent of operating temperature.

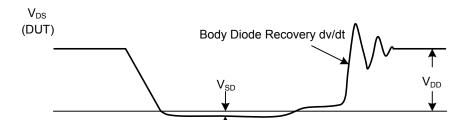
■ TEST CIRCUITS AND WAVEFORMS



Peak Diode Recovery dv/dt Test Circuit







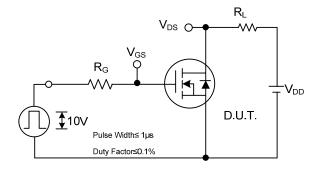
Voltage Drop
Peak Diode Recovery dv/dt Test Circuit and Waveforms

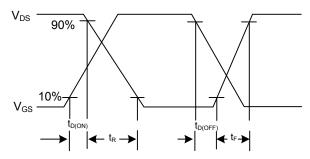
Body Diode Forward

Peak Diode Recovery dv/dt Waveforms

Preliminary

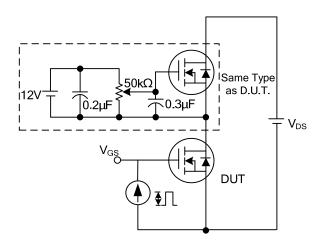
TEST CIRCUITS AND WAVEFORMS

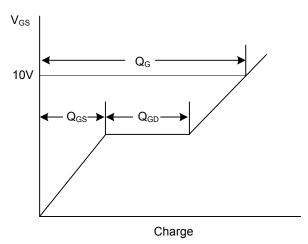




Switching Test Circuit

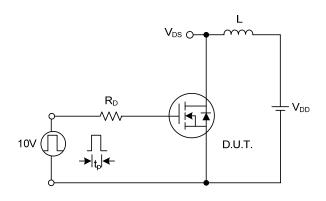
Switching Waveforms

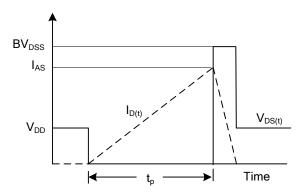




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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